



Fastställd 2018-05-16

Utgåva

1

Sida

1 (1+)

Ansvarig kommitté

SEK TK 82

© Copyright SEK. Reproduction in any form without permission is prohibited.

## Solcellsmoduler – Shuntdiod – Provning för termisk rusning

Photovoltaic modules – Bypass diode – Thermal runaway test

Som svensk standard gäller europastandarden EN 62979:2017. Den svenska standarden innehåller den officiella engelska språkversionen av EN 62979:2017.

## Nationellt förord

Europastandarden EN 62979:2017

består av:

- europastandardens ikraftsättningsdokument, utarbetat inom CENELEC
- IEC 62979, First edition, 2017 Photovoltaic modules Bypass diode Thermal runaway test

utarbetad inom International Electrotechnical Commission, IEC.

ICS 27.160.00

### Standarder underlättar utvecklingen och höjer elsäkerheten

Det finns många fördelar med att ha gemensamma tekniska regler för bl a mätning, säkerhet och provning och för utförande, skötsel och dokumentation av elprodukter och elanläggningar.

Genom att utforma sådana standarder blir säkerhetsfordringar tydliga och utvecklingskostnaderna rimliga samtidigt som marknadens acceptans för produkten eller tjänsten ökar.

Många standarder inom elområdet beskriver tekniska lösningar och metoder som åstadkommer den elsäkerhet som föreskrivs av svenska myndigheter och av EU.

## SEK är Sveriges röst i standardiseringsarbetet inom elområdet

SEK Svensk Elstandard svarar för standardiseringen inom elområdet i Sverige och samordnar svensk medverkan i internationell och europeisk standardisering. SEK är en ideell organisation med frivilligt deltagande från svenska myndigheter, företag och organisationer som vill medverka till och påverka utformningen av tekniska regler inom elektrotekniken.

SEK samordnar svenska intressenters medverkan i SEKs tekniska kommittéer och stödjer svenska experters medverkan i internationella och europeiska projekt.

#### Stora delar av arbetet sker internationellt

Utformningen av standarder sker i allt väsentligt i internationellt och europeiskt samarbete. SEK är svensk nationalkommitté av International Electrotechnical Commission (IEC) och Comité Européen de Normalisation Electrotechnique (CENELEC).

Standardiseringsarbetet inom SEK är organiserat i referensgrupper bestående av ett antal tekniska kommittéer som speglar hur arbetet inom IEC och CENELEC är organiserat.

Arbetet i de tekniska kommittéerna är öppet för alla svenska organisationer, företag, institutioner, myndigheter och statliga verk. Den årliga avgiften för deltagandet och intäkter från försäljning finansierar SEKs standardiseringsverksamhet och medlemsavgift till IEC och CENELEC.

### Var med och påverka!

Den som deltar i SEKs tekniska kommittéarbete har möjlighet att påverka framtida standarder och får tidig tillgång till information och dokumentation om utvecklingen inom sitt teknikområde. Arbetet och kontakterna med kollegor, kunder och konkurrenter kan gynnsamt påverka enskilda företags affärsutveckling och bidrar till deltagarnas egen kompetensutveckling.

Du som vill dra nytta av dessa möjligheter är välkommen att kontakta SEKs kansli för mer information.

SEK Svensk Elstandard

Box 1284 164 29 Kista Tel 08-444 14 00 www.elstandard.se

## EUROPEAN STANDARD NORME EUROPÉENNE EUROPÄISCHE NORM

EN 62979

October 2017

ICS 27.160

## **English Version**

# Photovoltaic module - Bypass diode - Thermal runaway test (IEC 62979:2017)

Essai d'emballement thermique portant sur les diodes de dérivation des modules photovoltaïques (IEC 62979:2017)

Photvoltaik-Module - Bypass-Diode - Prüfung des thermischen Durchgehens (IEC 62979:2017)

This European Standard was approved by CENELEC on 2017-09-14. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the CEN-CENELEC Management Centre has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Bulgaria, Croatia, Cyprus, the Czech Republic, Denmark, Estonia, Finland, Former Yugoslav Republic of Macedonia, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, the Netherlands, Norway, Poland, Portugal, Romania, Serbia, Slovakia, Slovenia, Spain, Sweden, Switzerland, Turkey and the United Kingdom.



European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

## **European foreword**

The text of document 82/1269/FDIS, future edition 1 of IEC 62979, prepared by IEC/TC 82 "Solar photovoltaic energy systems" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62979:2017.

The following dates are fixed:

| • | latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement | (dop) | 2018-06-14 |
|---|--|-------|------------|
| • | latest date by which the national standards conflicting with the document have to be withdrawn   | (dow) | 2020-09-14 |

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC shall not be held responsible for identifying any or all such patent rights.

## **Endorsement notice**

The text of the International Standard IEC 62979:2017 was approved by CENELEC as a European Standard without any modification.

## Annex ZA

(normative)

# Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu.

PublicationYearTitleEN/HDYearIEC/TS 61836-Solar photovoltaic energy systems ---

Terms, definitions and symbols

## CONTENTS

| H   | JKEW   | ORD   | 3  |
|-----|--------|---|----|
| IN  | TROD   | DUCTION   | 5  |
| 1   | Sco    | ppe   | 6  |
| 2   | Nor    | mative references   | 6  |
| 3   | Ter    | ms and definitions  | 6  |
| 4   | The    | ermal runaway test  | 7  |
|     | 4.1    | Diode thermal runaway   |    |
|     | 4.2    | Test conditions   |    |
|     | 4.3    | Preparation of test specimen                                      | 8  |
|     | 4.4    | Test equipment  | 9  |
|     | 4.5    | Test procedure  | 10 |
| 5   | Pas    | ss or fail criteria   | 12 |
| 6   | Tes    | st report   | 12 |
| Fi  | gure 1 | - Illustration of how thermal runaway occurs                      | 7  |
| Fi  | gure 2 | e – Circuit for measurement of Tlead and forward voltage          | 9  |
| Fi  | gure 3 | s – Circuit for flowing a forward current to the bypass diode     | 10 |
| Fi  | gure 4 | - Circuit for applying a reverse bias voltage to the bypass diode | 10 |
| Fi  | gure 5 | - The typical pattern of thermal runaway                          | 11 |
| Fig | gure 6 | - The pattern of non-thermal runaway                              | 11 |

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

## PHOTOVOLTAIC MODULES – BYPASS DIODE – THERMAL RUNAWAY TEST

## **FOREWORD**

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard IEC 62979 has been prepared by IEC technical committee 82: Solar photovoltaic energy systems.

The text of this International Standard is based on the following documents:

| FDIS         | Report on voting |
|--------------|------------------|
| 82/1269/FDIS | 82/1311/RVD      |

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

A bilingual version of this publication may be issued at a later date.

## INTRODUCTION

During the normal operation of PV modules the bypass diodes are reverse biased. When the PV module is partially shaded (for example by utility poles, buildings, or leaves), some of the cells in the PV module may not be able to produce the current being produced by the other cells in the series string. The shaded cells are then driven into reverse bias so the bypass diode of the shaded cell-string becomes forward bias protecting the shaded cells.

Under these circumstances, the temperature of the bypass diode increases due to the forward current flowing through the diode. It is in this condition that the diodes are tested in accordance with IEC 61215-2:2016, 4.18.1: Bypass diode thermal test. When the shade is removed, operating conditions return to normal and the bypass diode is again reversed biased.

Some of the diodes utilized as bypass diodes in PV modules have characteristics where the reverse bias leakage current increases with the diode temperature. So if the diode is already at an elevated temperature when reverse biased, there will be a substantial leakage current and the diode junction temperature can increase considerably. The worst case occurs when this heating exceeds the cooling capability of the junction box in which the diode is installed. As a result of this increasing temperature and leakage current, the diode can break down. These phenomena are called "thermal runaway". The thermal design of the bypass diode in the junction box shall be verified to ensure that thermal runaway does not occur.

## PHOTOVOLTAIC MODULES – BYPASS DIODE – THERMAL RUNAWAY TEST

### 1 Scope

This document provides a method for evaluating whether a bypass diode as mounted in the module is susceptible to thermal runaway or if there is sufficient cooling for it to survive the transition from forward bias operation to reverse bias operation without overheating.

This test methodology is particularly suited for testing of Schottky barrier diodes, which have the characteristic of increasing leakage current as a function of reverse bias voltage at high temperature, making them more susceptible to thermal runaway.

The test specimens which employ P/N diodes as bypass diodes are exempted from the thermal runaway test required herein, because the capability of P/N diodes to withstand the reverse bias is sufficiently high.

#### 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC TS 61836, Solar photovoltaic energy systems – Terms, definitions and symbols